

## **SEMICONDUCTOR TEST SYSTEM AND METHOD**

### **ABSTRACT**

The invention(s) relates to semiconductor test system and method that isolates and counteracts forces that bend test equipment resulting in improved manufacturing yield and throughput. The system includes a force retainer fixedly mounted on a material handler and a force locator positioned between the force retainer and a circuit board. Together, the force retainer and locator prevent the circuit board from bending. Other embodiments are illustrated and described.

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